

Appl. No. : Unassigned Confirmation No. Unassigned
First Inventor : AZIMANE, Mohamed IAP5 Rec'd PCT/PTO 30 AUG 2006
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Examiner : Unassigned

Docket No. : US04 0145 US3
Customer No. : 24738

Title: DFT Technique for Stressing Self-Timed Semiconductor
Memories to Detect Delay Faults

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims begin on page 3 of this paper.

Remarks/Arguments begin on page 4 of this paper.